

Title (en)

ELECTROMIGRATION TEST STRUCTURE FOR DETERMINING THE RELIABILITY OF WIRING

Title (de)

ELEKTROMIGRATIONS-TESTSTRUKTUR ZUR ERFASSUNG EINER ZUVERLÄSSIGKEIT VON VERDRAHTUNGEN

Title (fr)

STRUCTURE D'ESSAI D'ELECTROMIGRATION POUR LA DETERMINATION DE LA FIABILITE DE CABLAGES

Publication

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Application

**EP 01995590 A 20011207**

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Abstract (en)

[origin: WO02067318A2] The invention relates to an electromigration test structure for determining the reliability of wiring. An area which is to be tested, comprising an electromigration area (L) and an electromigration barrier area (V), is formed between a first and second test structure connection area (I1, I2). In order to assess life expectancy with precision and speed, a first and third sensor connector (S1, S3) is disposed in the immediate vicinity of the electromigration barrier area (V) and a second sensor connection (S2) is disposed on the second test structure (I2).

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